4 5-24.28.30 DE 8-21.7.86.00 DE 8-21.7.86.00

Form PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR INFORMATION DISCLOSURE STATEMENT (Use Several Sheets if Necessary)

APPLICANT: Frank K. Baker, Jr. et al.	2
	986
ATTY. DOCKET#: SC11150TH	APPL. #: 117772830
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FILING DATE: Concurrently Herewith	GROUP: Unknown 218

U.S. PATENT DOCUMENTS

EXAMIN			DOCUMENT	ISSUE	NAME	CLASS	SUBCLASS	FILING DATE
INITIAI	L		NUMBER	DATE				IF APPROPRIATE
m.	<i>y</i>	AA	5,828,603	Oct.27,'98	Pathak	365	185.21	Apr.23,'97
		AB	5,754,817	May 19,'98	Wells et al.	395	413	Feb.12,'97
		AC	5,502,678	Mar.26,'96	McClure	365	201	Sep.30,'94
		AD	5,498,559	Mar.12,'96	Chang	437	43	Jun.20,'94
		AE	5,325,335	Jun.28,'94	Ang et al.	365	205	Jun.5,'92
		AF	4,683,554	Jul.28,'87	Lockwood et al.	365	185	Sep.13,'85
m.	ν.	AG	4,316,264	Feb.16,'82	Harari	365	190	Jan.8,'80
		AH						
		AI						
		AJ						
		AK						
		AL						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE (#43)	COUNTRY	CLASS	SUBCLASS
	AM					
	AN					
	AO					
	AP					
	AQ					

OTHER INFORMATION (Including Author, Title, Date, Pertinent Pages, Etc.)

		OTTELL IN OTHER TOTAL CONTROL OF THE
M.N.	AR	Abstract, S.H. Wood et al., "Read disturb errors in a CMOS static RAM chip", 1989 IEEE Aerospace Applications Conference Digest (Cat. No.89TH0233-7), pg. 13.
M.N.	AS	Abstract, T. Endoh et al., "New write/erase operation technology for flash EEPROM cells to improve the read disturb characteristics", IEICE Transactions of Electronics, Vol.E80-C, No.10, pgs.1317-1323.
	AT	
	AU	
	AV	
EXAMINER	AW	DATE CONSIDERED 11 12 03

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